Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/690,779	TAKEUCHI ET AL.	
Examiner	Art Unit	
John S. Chu	1752	

	SEARCHED		
Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner
			

SEARCH (INCLUDING SEAR	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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EAST UPDATED	4/2014	pr	